

OptiMOS® Power-Transistor

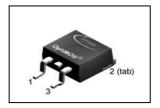
Features

- N-channel Logic Level Enhancement mode
- Automotive AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green package (lead free)
- Ultra low Rds(on)
- 100% Avalanche tested

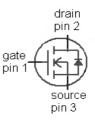
Product Summary

V _{DS}	75	V
$R_{\mathrm{DS(on),max}}$	20.5	mΩ
I _D	30	Α

PG-TO252-3-11



Туре	Package	Marking
IPD30N08S2L-21	PG-TO252-3-11	2N08L21



Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	T _C =25 °C, V _{GS} =10 V ¹⁾	30	А
		T _C =100 °C, V _{GS} =10 V ²⁾	30	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	120	1
Avalanche energy, single pulse	E _{AS}	/ _D =30A	240	mJ
Gate source voltage	V_{GS}		±20	V
Power dissipation	P _{tot}	T _C =25 °C	136	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 +175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R _{thJC}		-	-	1.1	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}		-	-	100	
SMD version, device on PCB	R_{thJA}	minimal footprint	-	-	75	
		6 cm ² cooling area ³⁾	-	-	50	

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	V _{GS} =0 V, I _D = 1 mA	75	ı	ı	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 80 \mu {\rm A}$	1.2	1.6	2.0	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =75 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	ı	0.01	1	μΑ
		$V_{\rm DS}$ =75 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C ²⁾	-	1	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	1	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =4.5 V, I _D =25 A	1	20.6	26	mΩ
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =25 A	-	15.9	20.5	mΩ



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	C iss		-	1650	-	pF
Output capacitance	C _{oss}	V_{GS} =0 V, V_{DS} =25 V, f=1 MHz	-	400	-	
Reverse transfer capacitance	C _{rss}		-	190	-	
Turn-on delay time	t _{d(on)}		-	9	-	ns
Rise time	t _r	V _{DD} =40 V, V _{GS} =10 V,	-	30	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =30 A, $R_{\rm G}$ =3.9 Ω	-	44	-	
Fall time	t _f		-	11	-	
Gate Charge Characteristics ²⁾						
Gate to source charge	Q _{gs}		-	6	6.8	nC
Gate to drain charge	Q_{gd}	V _{DD} =60 V, I _D =30 A,	ı	22	32	
Gate charge total	Q _g	V _{GS} =0 to 10 V	ı	56	72	
Gate plateau voltage	V _{plateau}		ı	3.5	1	V
Reverse Diode						
Diode continous forward current ²⁾	Is	−7 _C =25 °C	-	-	30	Α
Diode pulse current ²⁾	I _{S,pulse}		-	-	120	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =30 A, T _j =25 °C	-	0.9	1.3	V
Reverse recovery time ²⁾	t _{rr}	V_R =40 V, I_F = I_S , di_F / dt =100 A/ μ s	-	50	-	ns
Reverse recovery charge ²⁾	Qn	V _R =40 V, I _F =I _S , di _F /dt=100 A/μs	-	120	-	nC

¹⁾ Current limited by bondwire; with an RthJC = 1.1K/W the chip is able to carry ID= 54A at 25°C, for detailed information see app.-note ANPS071E available at www.infineon.com/optimos

²⁾ Defined by design. Not subject to production test.

³⁾ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm2 (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.



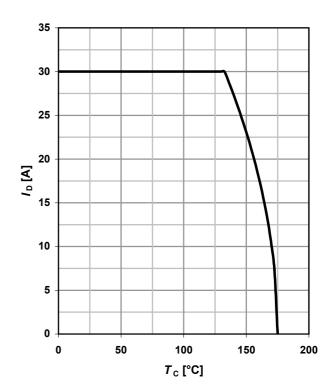
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$

160 140 120 100 P_{tot} [W] 80 60 40 20 0 0 50 100 200 150 *T*_c [°C]

2 Drain current

$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$



3 Safe operating area

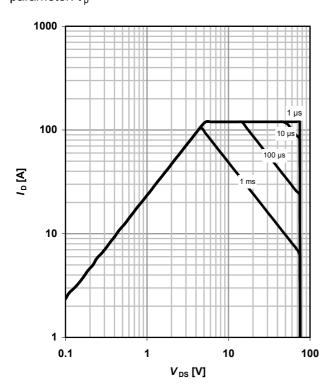
$$I_D = f(V_{DS}); T_C = 25 \,^{\circ}C; D = 0$$

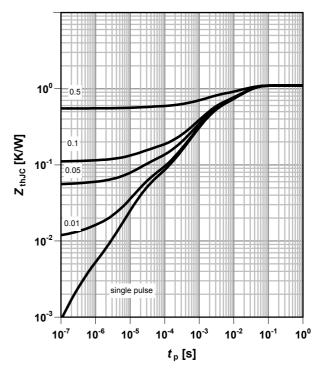
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter: $D = t_p/T$



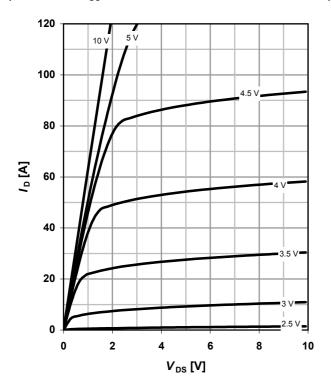




5 Typ. output characteristics

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm j} = 25 \,{}^{\circ}{\rm C}$

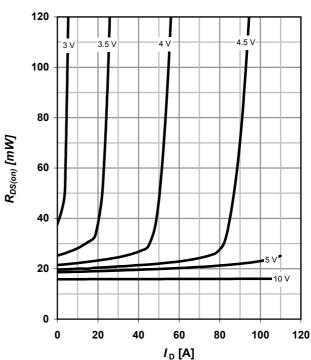
parameter: $V_{\rm GS}$



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25 \text{ }^{\circ}\text{C}$

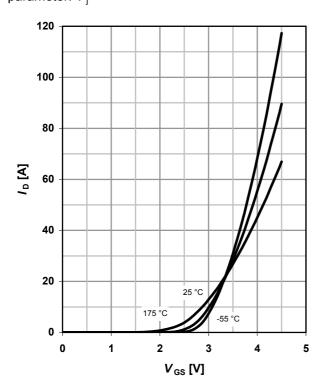
parameter: $V_{\rm GS}$



7 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 6V$

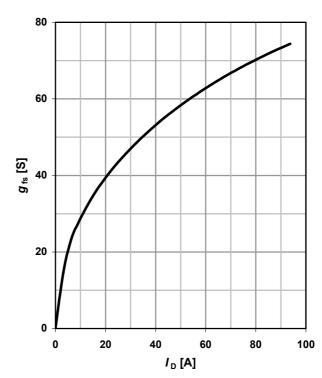
parameter: T_i



8 Typ. Forward transconductance

 $g_{fs} = f(I_D); T_j = 25^{\circ}C$

parameter: g fs

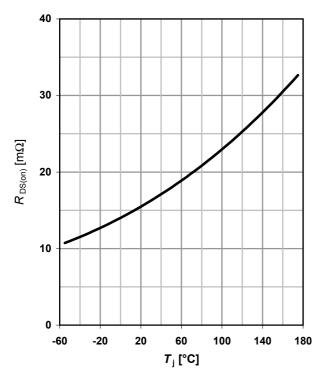




9 Typ. Drain-source on-state resistance

 $R_{DS(ON)} = f(T_j)$

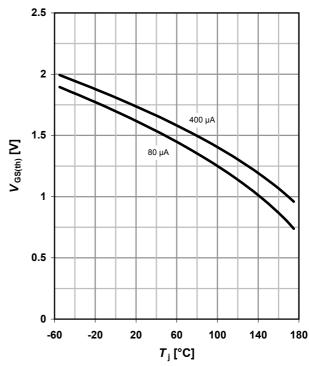
parameter: I_D = 25 A; V_{GS} = 10 V



10 Typ. gate threshold voltage

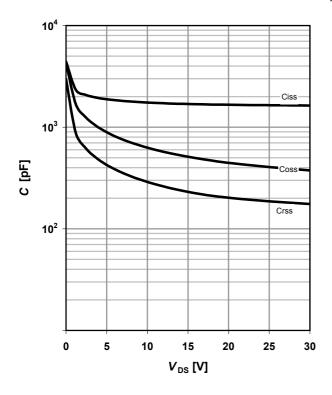
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D



11 Typ. capacitances

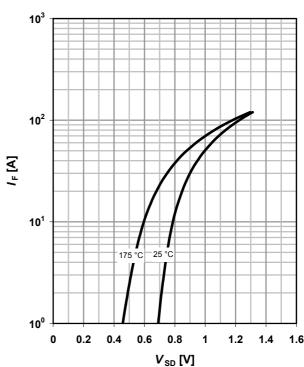
 $C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$



12 Typical forward diode characteristicis

 $IF = f(V_{SD})$

parameter: T_i





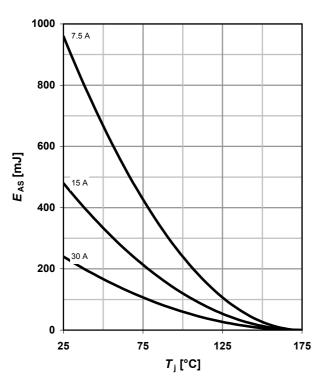
13 Typical avalanche energy

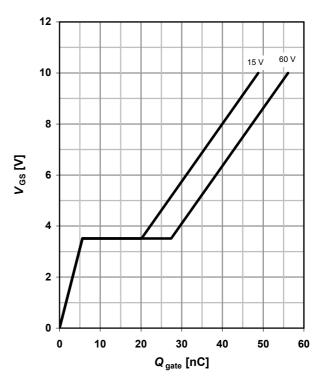
 $E_{AS} = f(T_i)$

parameter: I_D

14 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 30 A pulsed$

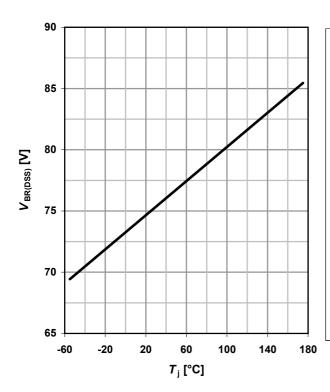


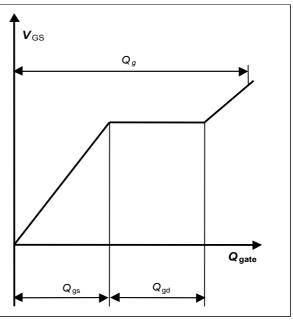


15 Typ. drain-source breakdown voltage

 $V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$

16 Gate charge waveforms







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